

FIG.1

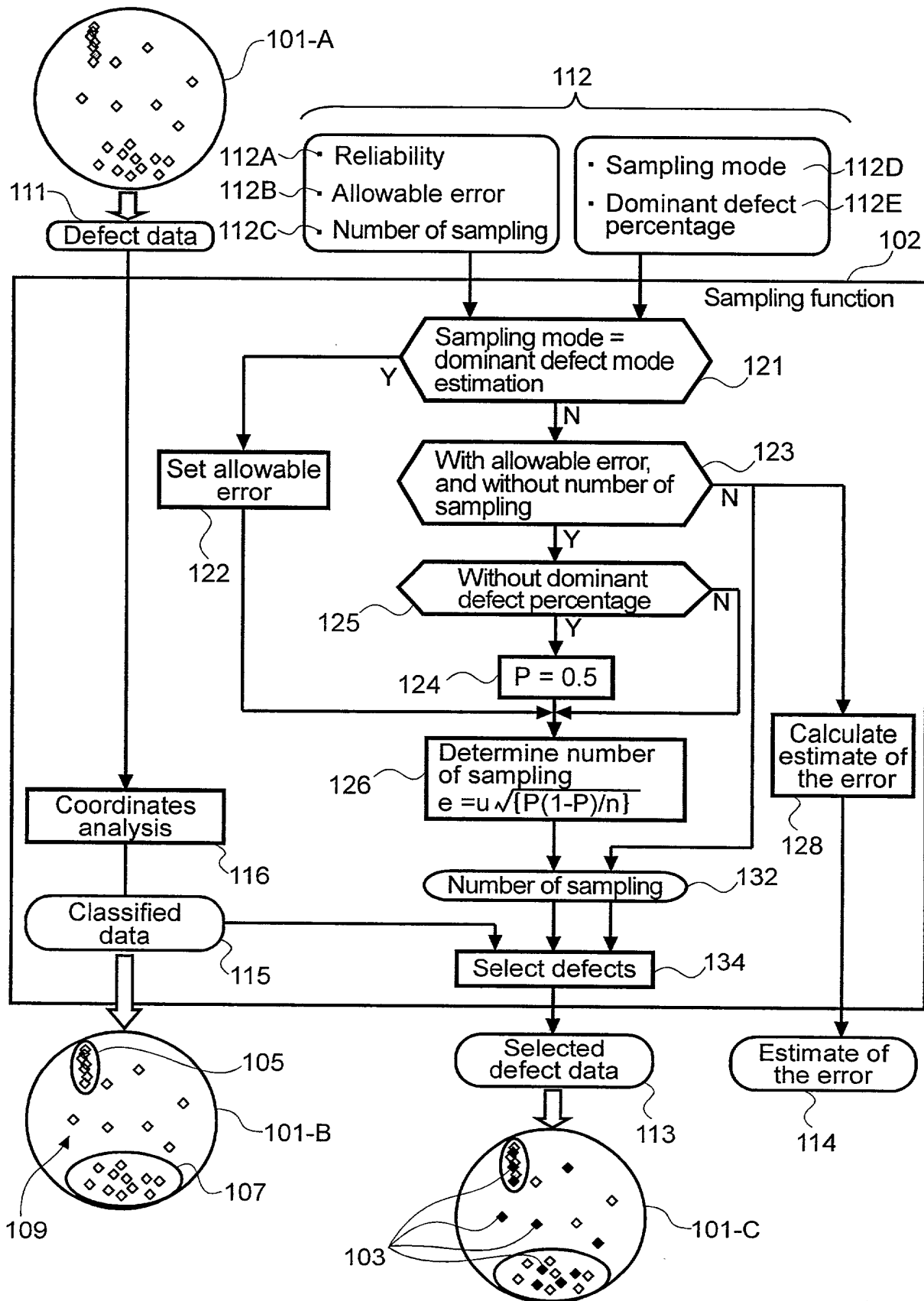


FIG.2

202

Reliability	U
0.80	1.28
0.90	1.65
0.98	2.33
...	...

FIG.3

302

326

324

322

332

336

334

U=2.33												
U=1.65												
U=1.28												
n	P											
	0.1	0.2	0.3	0.4	0.5	0.6	0.7	0.8	0.9			
	59	105	138	158	164	158	138	105	59			
	15	26	35	39	41	39	35	26	15			
e	4	7	9	10	10	10	9	7	4			
...	...	...	...	...	...	...	...	...	...			

FIG.4

402 {

404 {

406 {

408 {

Reliability  % 442

Whole wafer  461

Classified Regions  481

High Density { 482

Dense { 484

Sparse { 486

Sampling mode  ▼ 462

D.D. %  % 464

error %  % 466

# Samples  Pts. 468

483

485

487

489

OK  421

CANCEL  423

FIG.5

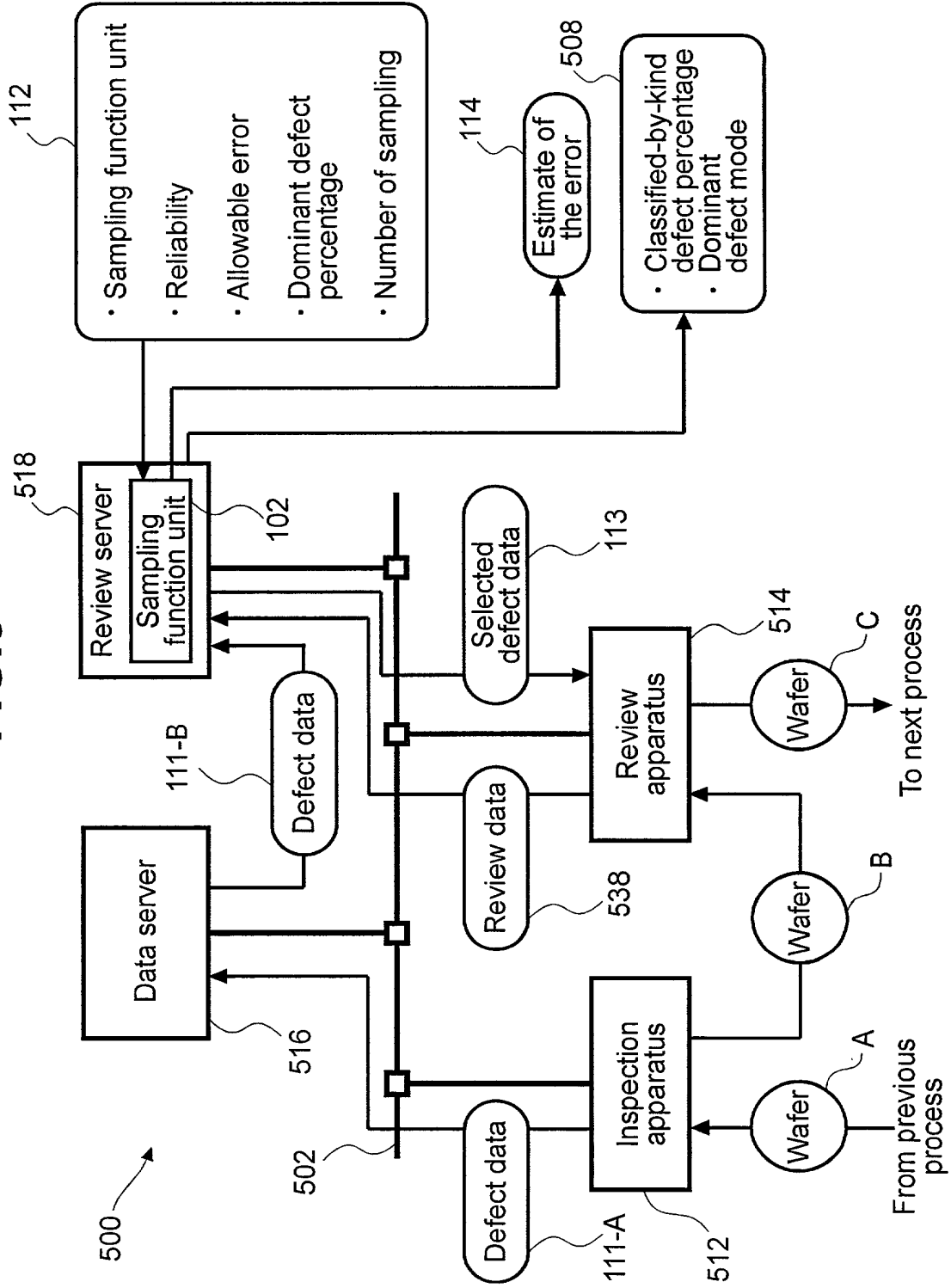


FIG.6

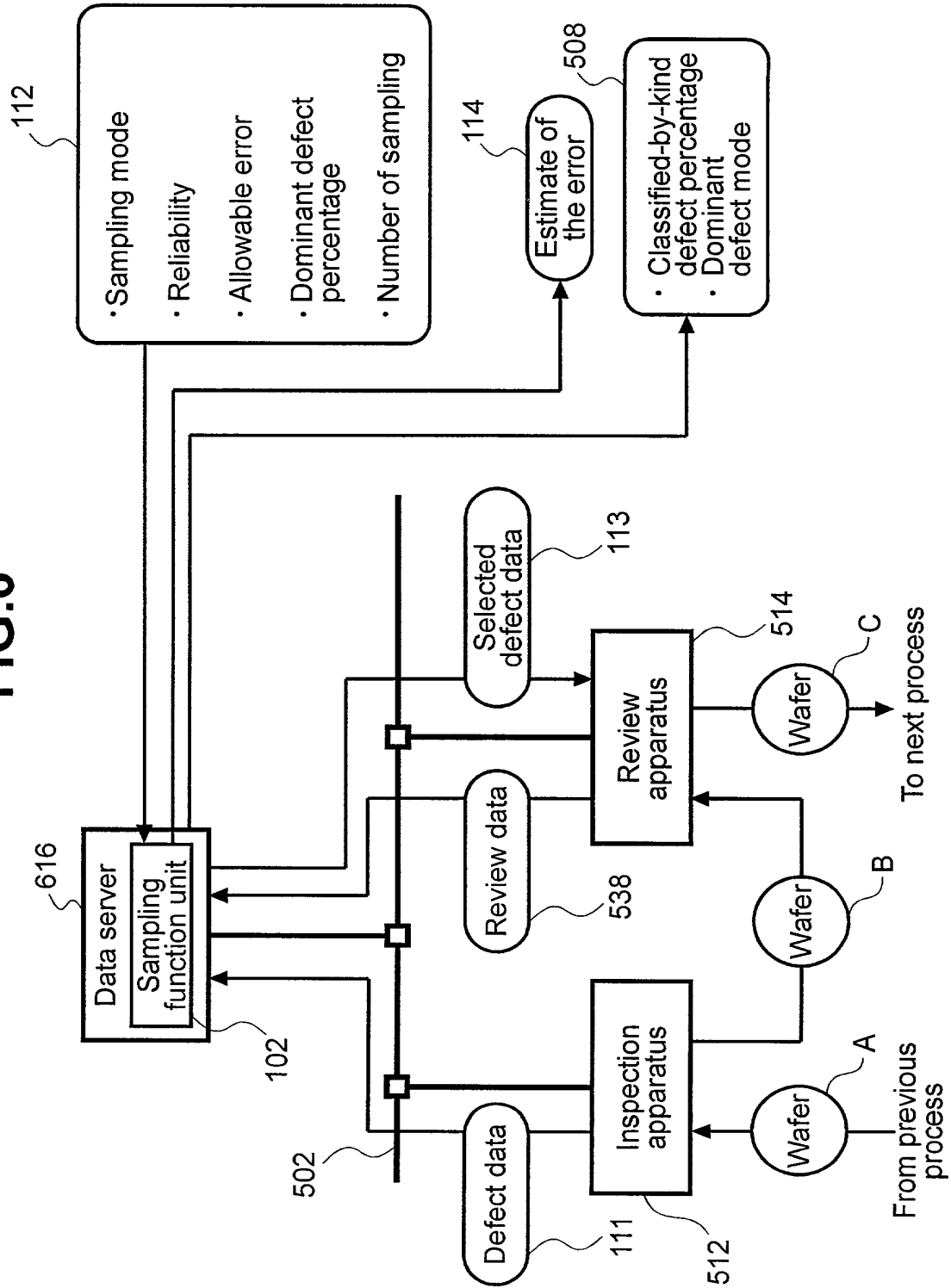


FIG.7

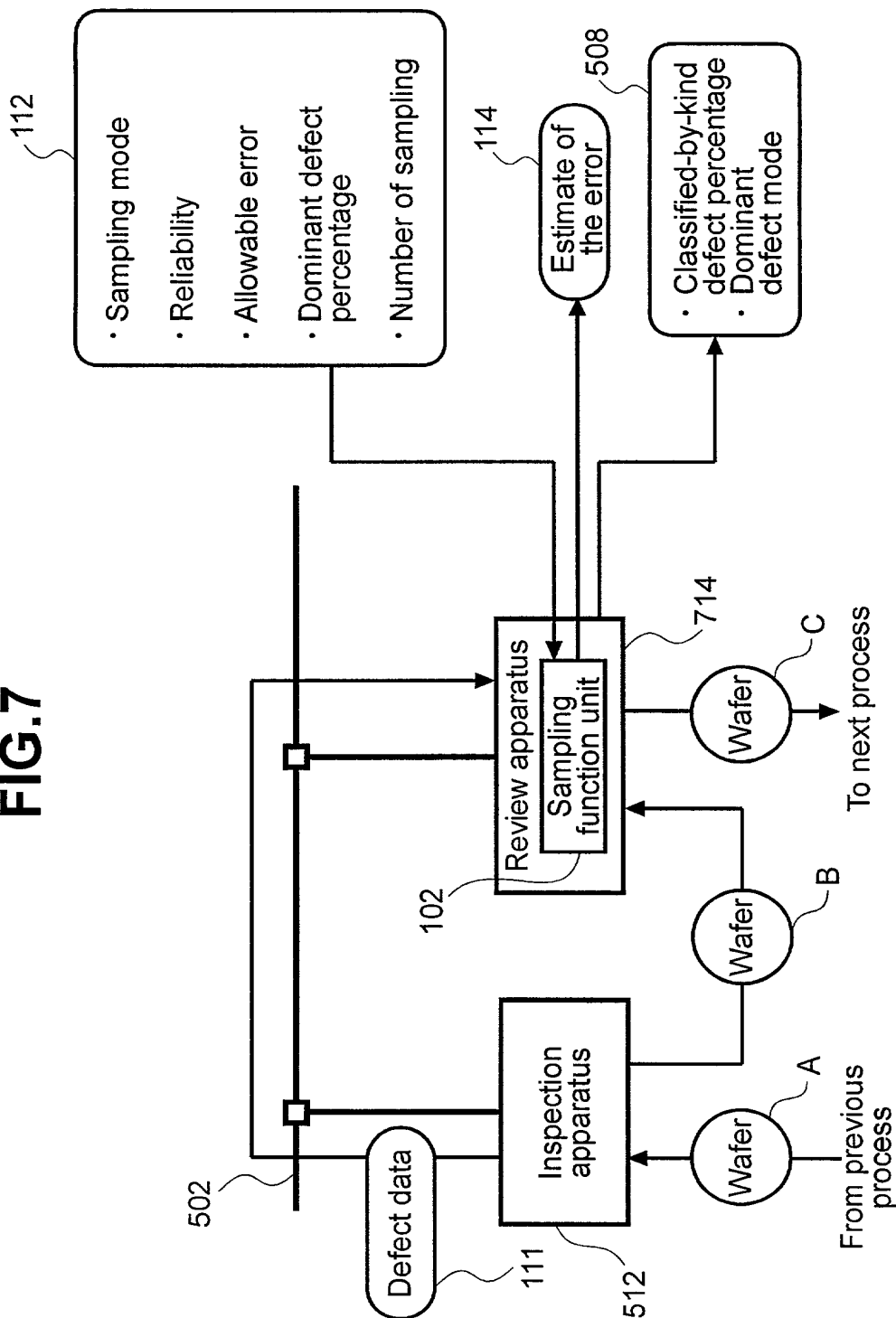


FIG.8

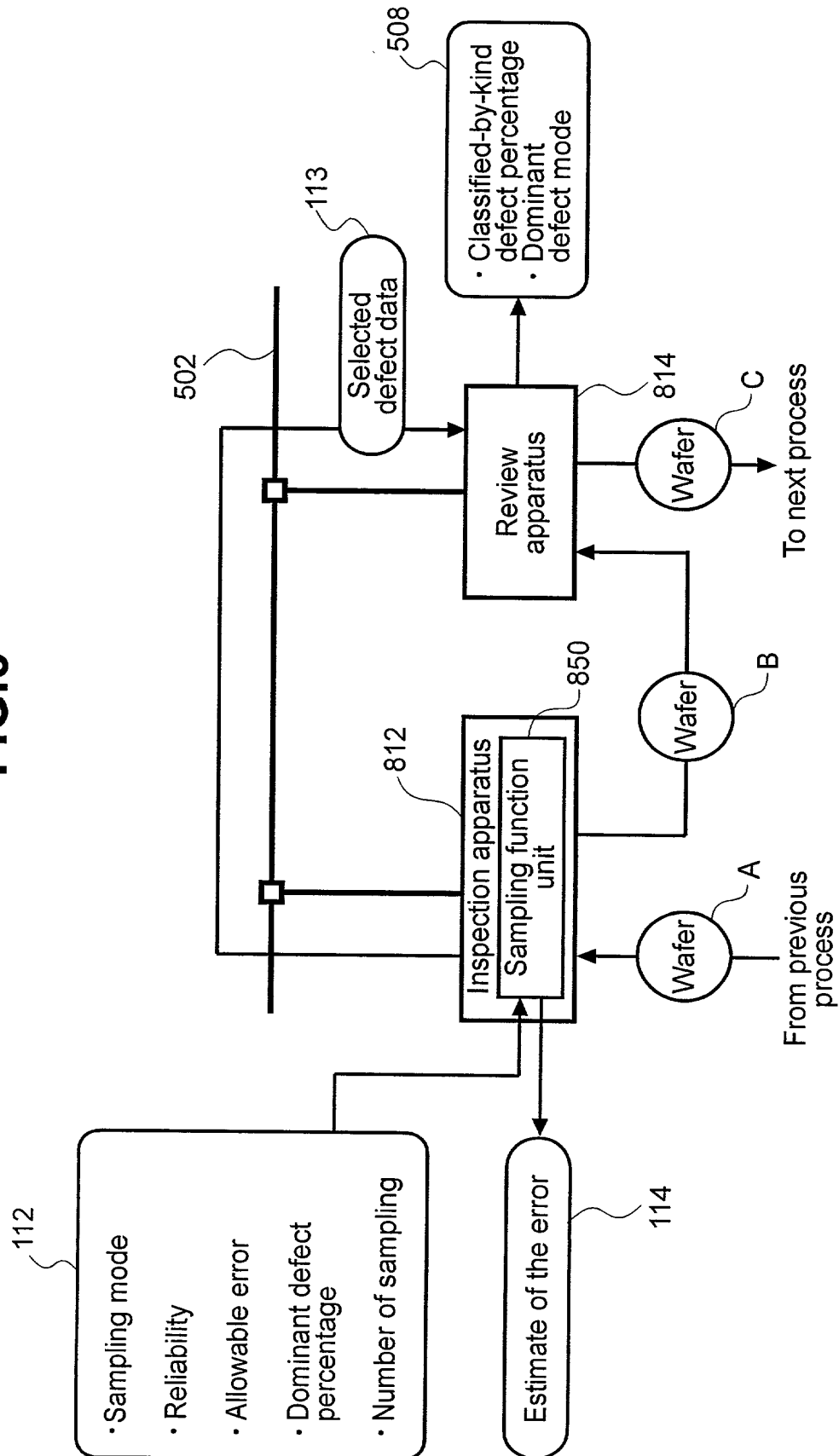
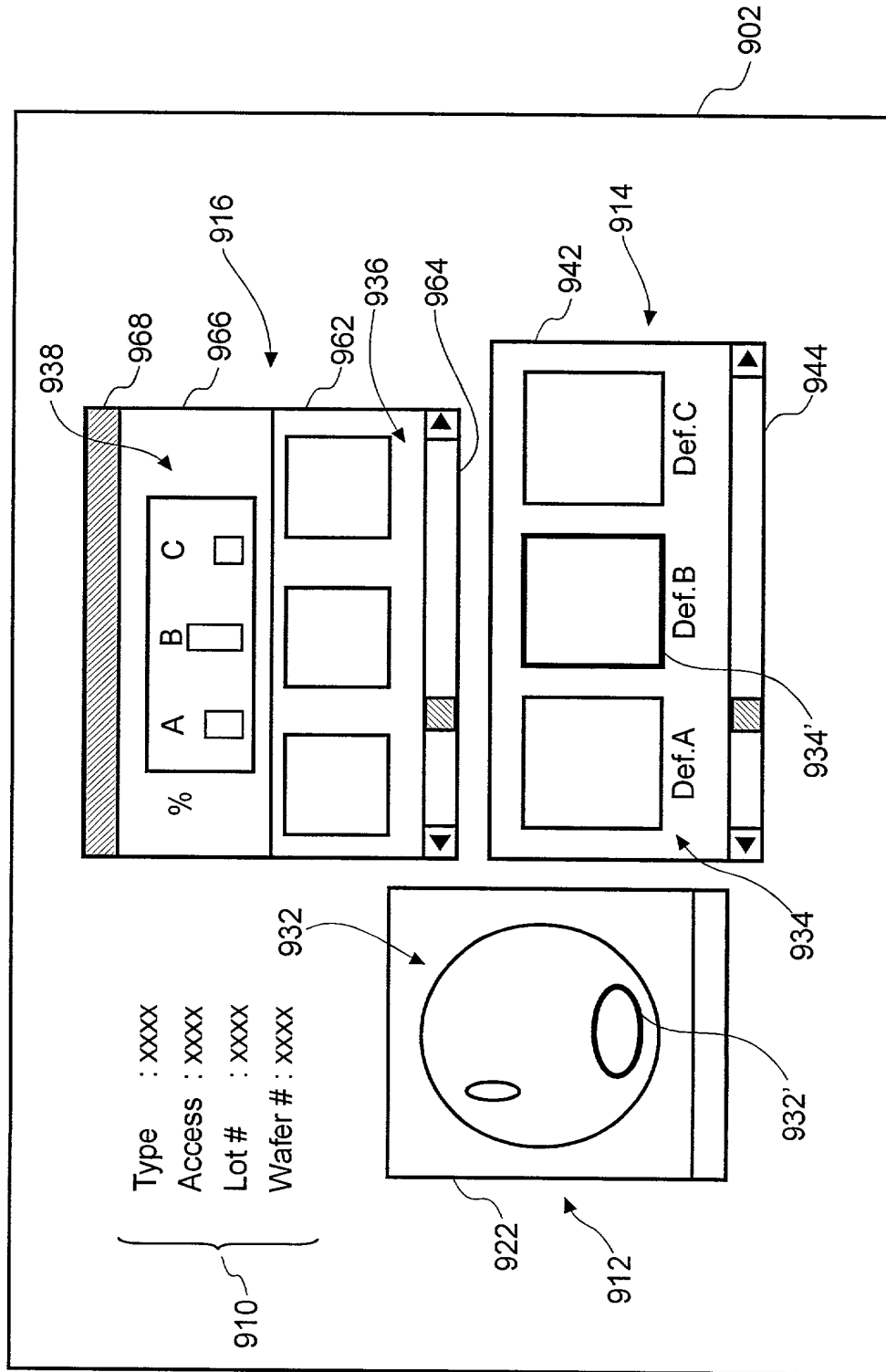
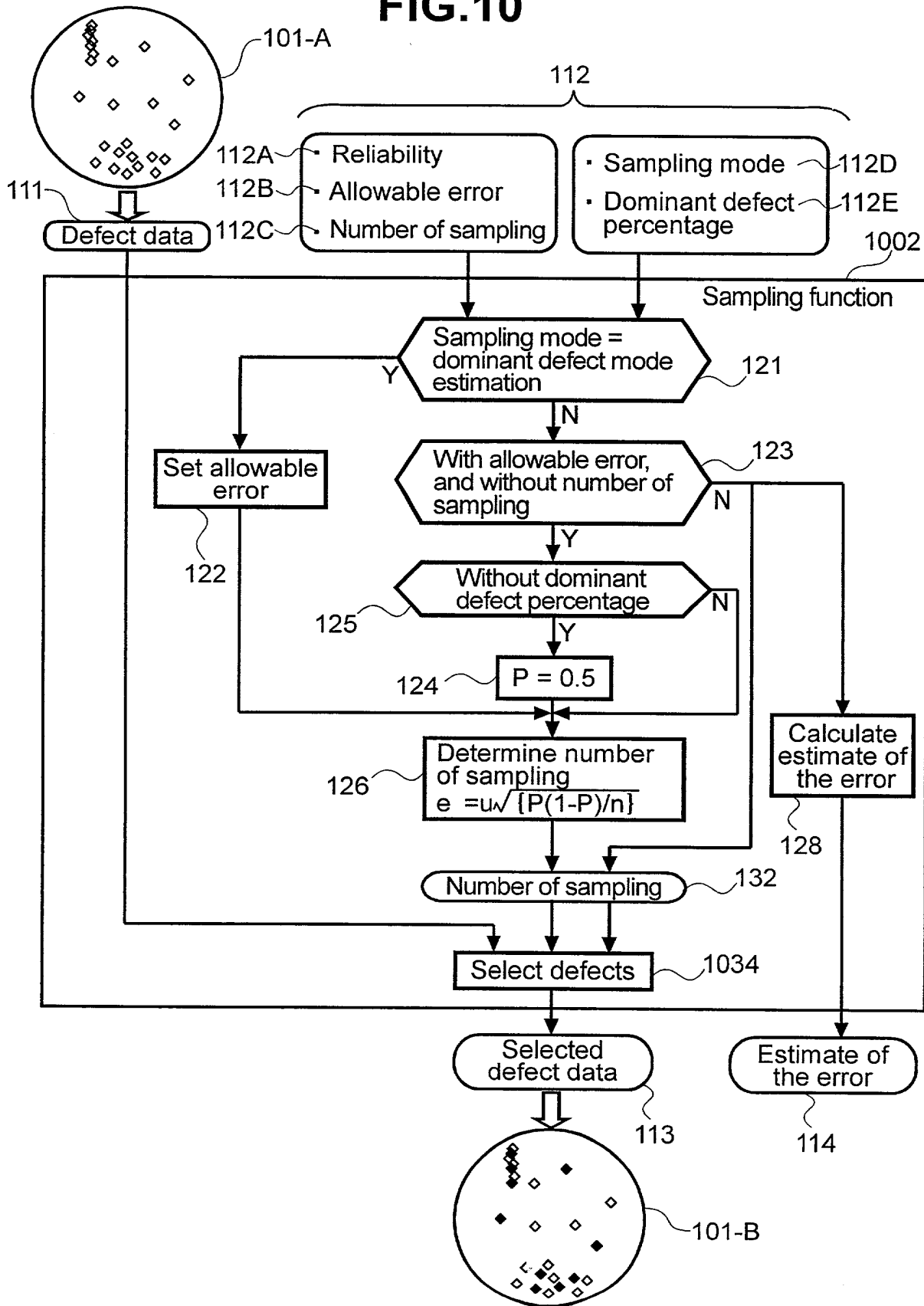


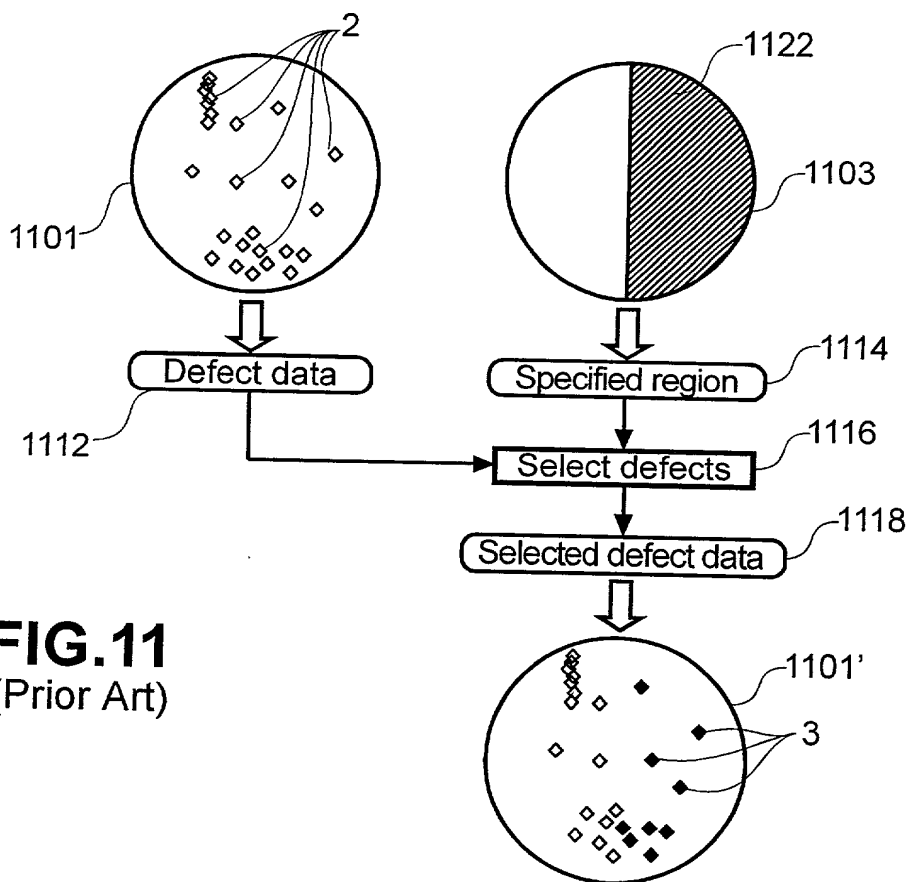
FIG.9



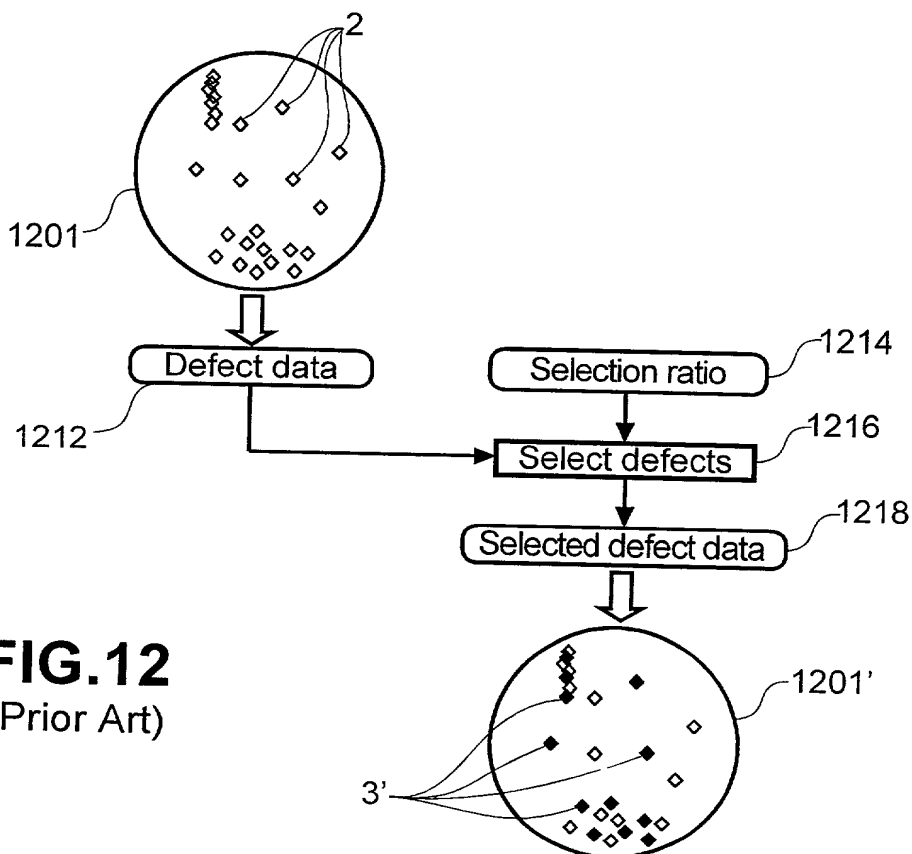


**FIG.10**





**FIG. 11**  
 (Prior Art)



**FIG. 12**  
 (Prior Art)